## PATENT ABSTRACTS OF JAPAN

(11)Publication number:

01-236657

(43) Date of publication of application: 21.09.1989

(51)Int.CI.

H01L 29/80 H01L 27/08

(21)Application number: 63-064041

(71)Applicant: TOSHIBA CORP

(22)Date of filing:

17.03.1988

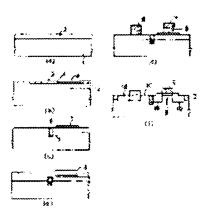
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## (54) SEMICONDUCTOR DEVICE AND MANUFACTURE THEREOF

## (57)Abstract:

PURPOSE: To make it possible to form MESFETs whose threshold voltages are different form each other, on the same substrate by a method wherein step differences are provided on the surface of a semiconductor film by further laminating it with a part of a layer to become a channel active layer by a crystal growth technique which performs control at the level of an atomic layer on an epitaxial active layer which is controlled and deposited at the level of an atomic layer.

CONSTITUTION: An N-type GaAs epitaxial layer 2 is formed on a semi-insulative GaAs substrate 1 by a technique of superposing atomic planes one sheet by one sheet and a prescribed part only of an epitaxial layer 5 of the level of an atomic layer is further deposited on the layer 2 using this crystal growth technique. Then, a high-melting point metal film or a high-melting point metal compound film 8 is formed as a gate electrode, an insulating film 9 is deposited thereon to perform a gate electrode processing and the electrode 8 is selfaligned to form source/drain N+ layers 10 by implanting Si ions. Thereby, MESFETs(Metal Semiconductor Field Effect Transistors), whose threshold voltages are different from each other, can be manufactured on the same substrate.



## **LEGAL STATUS**

[Date of request for examination]

[Date of sending the examiner's decision of rejection]

[Kind of final disposal of application other than the examiner's decision of rejection or application converted registration]

[Date of final disposal for application]

[Patent number]

[Date of registration]

[Number of appeal against examiner's decision of rejection]

[Date of requesting appeal against examiner's decision of rejection]

[Date of extinction of right]